

IN THE SPECIFICATION

Please amend the specification as follows:

Page 6, insert after line 9,

--BRIEF DESCRIPTION OF THE DRAWINGS

A more complete appreciation of the invention and many of the attendant advantages thereof will be readily obtained as the same become better understood by reference to the following detailed description when considered in connection with the accompanying drawings, wherein:

Fig. 1 shows the schematic setup of the experimental arrangement. In a downstream filter unit, the pulverulent product is separated from the gaseous substances.

Figs. 2a and 2b show transmission electron micrographs at different resolutions (bar corresponds to 50 nm in fig. 2a and 0.5  $\mu\text{m}$  in fig. 2b) of the nanoscale silicon particles Si<sub>3</sub>.

Figs. 3 to 14 are referenced in Tables 4 and 5, respectively. Table 4 shows the experimental parameters with an experimental procedure according to the classical mode, and table 5 shows the experimental parameters with an experimental procedure according to the capacitance-limited mode.--